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# PTP13N50B PTA13N50B

### **500V N-Channel MOSFET**

## **General Features**

- Proprietary New Planar Technology
- R<sub>DS(ON),typ</sub> =0.40 Ω@V<sub>GS</sub>=10V
- Low Gate Charge Minimize Switching Loss
- Fast Recovery Body Diode

# **Applications**

- ATX Power
- LCD Panel Power

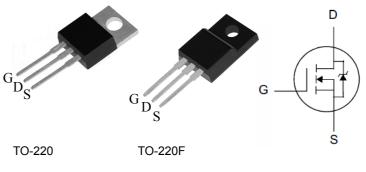
## **Ordering Information**

Part Number	Package	Brand
PTP13N50B	TO-220	ï
PTA13N50B	TO-220F	ï

# **Absolute Maximum Ratings**

### Dead Free Package and Finish

BV <sub>DSS</sub>	R <sub>DS(ON),typ.</sub>	I <sub>D</sub>	
500V	0.40Ω	13A	



Package Not to Scale

 $T_C \mbox{=} 25\,^\circ\! {\rm C}$  unless otherwise specified

Symbol	Parameter	PTP13N50B	PTA13N50B	Unit
V <sub>DSS</sub>	Drain-to-Source Voltage <sup>[1]</sup>	50	00	V
V <sub>GSS</sub>	Gate-to-Source Voltage	±30		v
I <sub>D</sub>	Continuous Drain Current	1	3	٨
I <sub>DM</sub>	Pulsed Drain Current at V <sub>GS</sub> =10V <sup>[2]</sup>	4	8	A
E <sub>AS</sub>	Single Pulse Avalanche Energy	562		mJ
dv/dt	Peak Diode Recovery dv/dt <sup>[3]</sup>	5.0		V/ns
П	Power Dissipation	190	65	W
P <sub>D</sub>	Derating Factor above 25℃	1.52	0.52	W/℃
T <sub>L</sub> T <sub>PAK</sub>	Maximum Temperature for Soldering Leads at 0.063in (1.6mm) from Case for 10 seconds, Package Body for 10 seconds	300 260		°C
T <sub>J</sub> & T <sub>STG</sub>	Operating and Storage Temperature Range	-55 to 150		

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

## **Thermal Characteristics**

Symbol	Parameter	PTP13N50B	PTA13N50B	Unit
R <sub>θJC</sub>	Thermal Resistance, Junction-to-Case	0.66	1.92	
R <sub>θJA</sub>	Thermal Resistance, Junction-to-Ambient	62	100	°C <b>/W</b>

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# **Electrical Characteristics**

#### **OFF Characteristics** T<sub>J</sub> =25 °C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	500			V	$V_{GS}$ =0V, I <sub>D</sub> =250uA
	Drain to Source Lookage Current			1	uA -	V <sub>DS</sub> =500V, V <sub>GS</sub> =0V
I <sub>DSS</sub>	Drain-to-Source Leakage Current			100		V <sub>DS</sub> =400V, V <sub>GS</sub> =0V, T <sub>J</sub> =125℃
1	Cate to Source Leakage Current			+100	nA	V <sub>GS</sub> =+30V, V <sub>DS</sub> =0V
I <sub>GSS</sub>	Gate-to-Source Leakage Current			-100		V <sub>GS</sub> =-30V, V <sub>DS</sub> =0V

### **ON Characteristics**

T₁ =25°C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions
R <sub>DS(ON)</sub>	Static Drain-to-Source On-Resistance <sup>[4]</sup>		0.40	0.50	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =6.0A
$V_{GS(TH)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS}$ = $V_{GS}$ , $I_D$ =250uA
gfs	Forward Transconductance <sup>[4]</sup>		20		S	VDS=20V,ID=13A

### **Dynamic Characteristics**

Essentially independent of operating temperature Symbol Parameter Min. Unit **Test Conditions** Typ. Max. Ciss Input Capacitance 1180 \_\_\_ \_\_\_ V<sub>GS</sub>=0V, V<sub>DS</sub>=25V, f=1.0MH<sub>Z</sub> C<sub>rss</sub> **Reverse Transfer Capacitance** 13 \_\_\_ -pF Coss 120 **Output Capacitance** \_\_\_ --- $Q_{g}$ **Total Gate Charge** 32 ------ $\label{eq:VDD} \begin{array}{l} V_{DD} \mbox{=} 400 V, \\ I_D \mbox{=} 13 A, \ V_{GS} \mbox{=} 0 \ to \ 10 V \end{array}$ Q<sub>gs</sub> Gate-to-Source Charge 7 -nC \_\_\_ Gate-to-Drain (Miller) Charge 16  $Q_{gd}$ \_\_\_ \_\_\_

### **Resistive Switching Characteristics**

Essentially independent of operating temperature

	Vesistive Owitching Onalacteristics					
Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions
td(ON)	Turn-on Delay Time		21		nS	V <sub>DD</sub> =250V, I <sub>D</sub> =13A, V <sub>GS</sub> = 10V RG=25 Ω
trise	Rise Time		13			
td(OFF)	Turn-Off Delay Time		88			
tfall	Fall Time		30			

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# **PTP13N50B PTA13N50B**

### **Source-Drain Body Diode Characteristics**

#### $T_J {=} 25\,^\circ\!\! {\rm C}$ unless otherwise specified

Symbol	Parameter	Min	Тур.	Max.	Unit	Test Conditions
I <sub>SD</sub>	Continuous Source Current <sup>[4]</sup>			13	^	Integral PN-diode in MOSFET
I <sub>SM</sub>	Pulsed Source Current <sup>[4]</sup>			48	A	
V <sub>SD</sub>	Diode Forward Voltage			1.4	V	I <sub>S</sub> =13A, V <sub>GS</sub> =0V
trr	Reverse recovery time		310		ns	V <sub>GS</sub> =0V ,IF=13A,
Qrr	Reverse recovery charge		4.0		uC	di⊧/dt=100A/µs

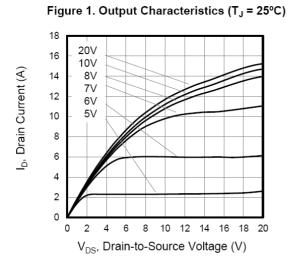
Note:

[1] T\_J=+25 $^\circ\!\!\mathrm{C}$  to +150 $^\circ\!\!\mathrm{C}$ 

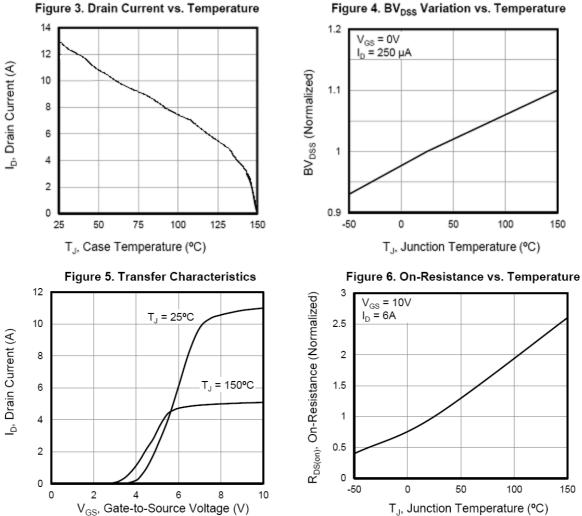
[2] Repetitive rating; pulse width limited by maximum junction temperature.

- [3] IsD= 13A ,di/dt < 100 A/μs, VDD < BVDss, TJ=+150 ℃. [4] Pulse width≤380μs; duty cycle≤2%.

# **Typical Characteristics**







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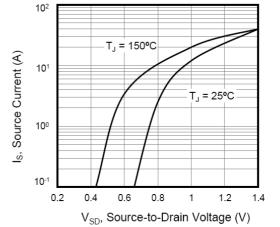
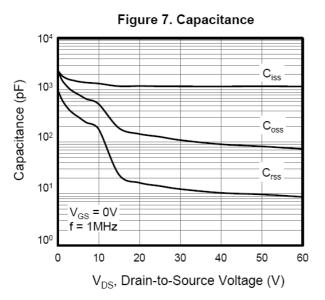


Figure 2. Body Diode Forward Voltage

## **Typical Characteristics**(Cont.)



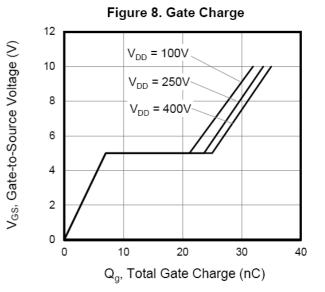
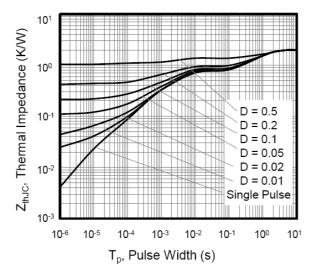


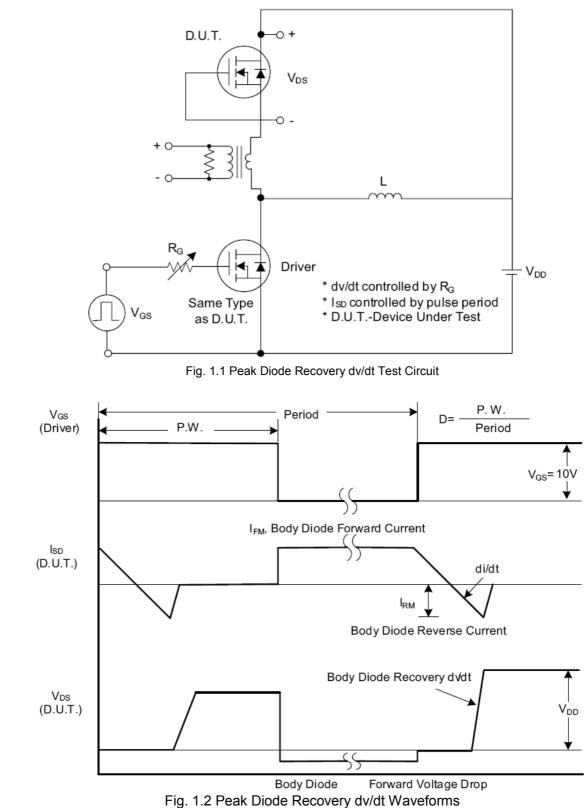
Figure 9. Transient Thermal Impedance



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### **Test Circuits and Waveforms**



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### Test Circuits and Waveforms (Cont.)

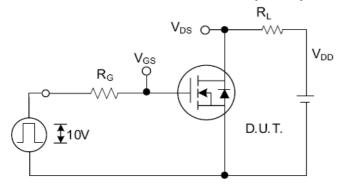


Fig. 2.1 Switching Test Circuit

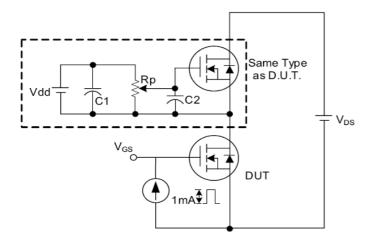


Fig. 3.1 Gate Charge Test Circuit

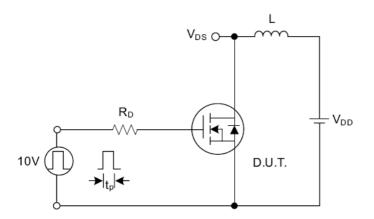


Fig. 4.1 Unclamped Inductive Switching Test Circuit

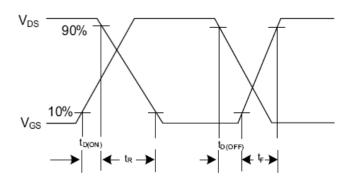


Fig. 2.2 Switching Waveforms

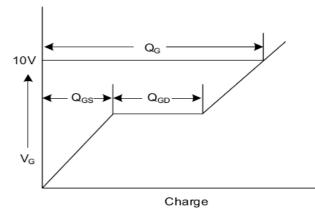
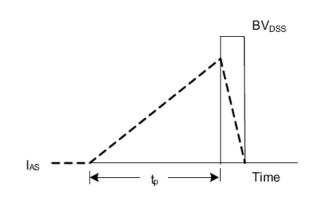


Fig. 3.2 Gate Charge Waveform





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